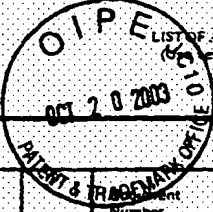
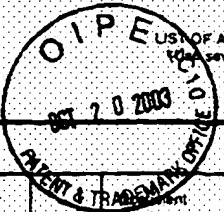



Form PTO-1 449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M22-1363		SERIAL NO. 09/512 966	
 LIST OF ART CITED BY APPLICANT (On several sheets if necessary)				APPLICANT David Hembree		GROUP 2856	
				FILING DATE February 24, 2000			
U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
VN	AA 5,612,574	3/16/97	Summerfelt et al.				
VN	AB 5,719,333	2/17/98	Hosor et al.				
VN	AC 5,831,333	11/3/98	Malladi et al.				
VN	AD 5,919,548	7/6/99	Barron et al.				
VN	AE 5,551,283	9/3/96	Manaka et al.				
VN	AF 5,492,011	2/20/96	Amano et al.				
	AG						
	AH						
	AJ						
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AK						
	AL						
	AM						
	AO						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
VN	AP		"NTC and PTC Thermistors": http://www.thermodisc.com/ntc_ptc.html ; 1/7/98; 2 pages.				
VN	AR		"DI-5B35 Linearized 4-Wire RTD Input": http://www.dataq.com/di5b35.html ; 1/7/98; 2 pages.				
VN	AS		"RTD": http://www.mosensors.com/rtds.html ; 1/7/98; 3 pages.				
VN	AT		"Low Cost Thermal-Ribbon (TM) uses thin film RTD": http://www.minco.com/vs17624nr.html ; 1/7/98; 1 page.				
VN	AU		"Silicon Processing for the VLSI Era"; Volume 1 - Process Technology, Second Edition, S. Wolf et al.; 2000; pps 22-25 and pps. 841-845.				
EXAMINER <i>vinh Nguyen</i>				DATE CONSIDERED <i>01/22/04</i>			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 608; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1363		SERIAL NO. 09/512 958	
 LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.		PRIORITY GROUP 2829	
				FILING DATE February 24, 2000		PRIORITY GROUP 2829	
U.S. PATENT DOCUMENTS							
Examiner Initial	Assignment Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
VN	AA 3,710,251	1/9/1973	Hegge et al.				
	AB						
	AC						
	AD						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
EXAMINER <i>mark Nguyen</i>			DATE CONSIDERED 01/22/04				
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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1363		SERIAL NO. 05/512 568	
 LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.		PRIORITY GROUP 2853	
				FILING DATE February 24, 2000			
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
W	AA 4,355,463	10/26/1982	Burns				
	AB						
	AC						
	AD						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AE						
	AF						
	AG						
	AH		E-085425944				
	AI						
	AJ						
	AK						
	AL						
EXAMINER <i>mh Nguy</i>				DATE CONSIDERED 01/22/04			
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PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
M122-1363SERIAL NO.
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Micron Technology, Inc.FILING DATE
February 24, 2000PRIORITY GROUP
2858

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA	4,912,600	3/1990	Jeeger et al.	361	700	
VN	AB	5,436,494	7/1995	Mosleh	257	467	
VX	AC	5,969,639	10/1999	Lauf et al.	340	87-17	
	AD						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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EXAMINER

anh Nguyen

DATE CONSIDERED

01/22/04

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